

## SOLUTION SERIES 6

### Exercise 1: Absorption

- a) Which thickness of material do you need to absorb 90 % of the light with  $\lambda = 500 \text{ nm}$  and  $1000 \text{ nm}$  in amorphous Si and in crystalline Si. Absorption coefficients are given in Tab. 1

Table 1: Absorption coefficients

$\lambda[nm]$	$\alpha$ for a-Si:H [ $cm^{-1}$ ]	$\alpha$ for c-Si [ $cm^{-1}$ ]
500	$2 \cdot 10^5$	$10^4$
1000	0.9	80

### *Solution:*

From the Beer-Lambert law:

$$I(x) = I_0 e^{-\alpha x [\frac{W}{m^2}]}$$

We deduce

$$x = \frac{\ln[0.1]}{-\alpha} [cm]$$

The absorption depths at which 90 % of the light is absorbed, for the different materials and wavelengths are given in Tab. 2

Table 2: Absorption depths at which 90 % of light is absorbed

$\lambda[nm]$	$x$ for a-Si:H [m]	$x$ for c-Si [m]
500	$1.12 \times 10^{-7}$	$2.3 \times 10^{-6}$
1000	$2.56 \times 10^{-2}$	$2.88 \times 10^{-4}$

- b) Draw the absorption profile for an intensity  $F_0$  in a semi infinite wafer with a reflection of 10 % with  $\lambda = 500 \text{ nm}$  and  $1000 \text{ nm}$  in amorphous Si and in crystalline Si.

### *Solution:*

In Fig 1, the intensity profile is drawn for two wavelengths in a-Si:H and c-Si materials.

- c) Taking the results of a) & b) into account, what are options to increase the absorption to more than 99% in the films without making them thicker than what you calculated in a) ?

### *Solution:*

Finally there are only two ways to achieve this (in classical ray optics):

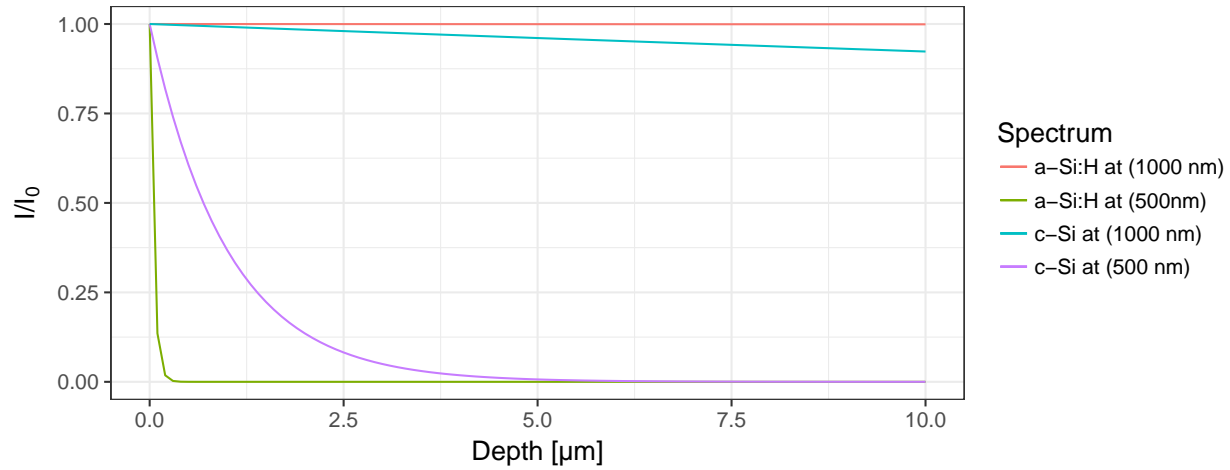


Figure 1: Light intensity decay in a-Si and c-Si for different wavelengths.

- (a) reduce front reflection losses
  - use an antireflection coating
  - texture the front surface to create multiple bounces
- (b) use a back "mirror", e.g., silver electrode to at least double the optical path
  - texture also the BACK surface to lengthen the optical path beyond a factor of 2, e.g., in crystalline silicon path length extension ca. 4x

### Exercise 2: Antireflection layer

Consider a multilayer stack with refractive indices  $n_1$ ,  $n_2$ , and  $n_3$ . The Fresnel equation of reflection at normal incidence for two layers  $i$  and  $j$  is  $r_{ij} = ((n_i - n_j)/(n_i + n_j))^2$ . To achieve minimal reflection the second reflection  $r_{23}$ , should nullify  $r_{21}$ . Derive a condition linking  $n_1$ ,  $n_2$ , and  $n_3$ .

**Solution:** At the first interface ( $n_1, n_2$ ), the reflection coefficient can be given as:

$$r_{21} = r_{12} = ((n_1 - n_2)/(n_1 + n_2))^2$$

At the second interface ( $n_2, n_3$ ), the reflection coefficient can be given as:

$$r_{23} = ((n_2 - n_3)/(n_2 + n_3))^2$$

In order to achieve minimum reflection, we want these two reflection coefficients to have the same magnitude and opposite sign, so the reflected waves destructively interfere:

$$|r_{12}| = |r_{23}|$$

Substitute the expressions for  $r_{12}$  and  $r_{23}$  and take the square root:

$$|(n_1 - n_2)/(n_1 + n_2)| = |(n_2 - n_3)/(n_2 + n_3)|$$

Now, cross-multiply:

$$(n_1 - n_2)(n_2 + n_3) = (n_1 + n_2)(n_2 - n_3)$$

Expanding both sides:

$$n_1n_2 - n_1n_3 - n_2^2 + n_2n_3 = n_1n_2 + n_1n_3 - n_2^2 - n_2n_3$$

Now, rearrange the equation to group the terms:

$$2n_1n_3 = 2n_2^2$$

Divide both sides by 2 and take the square root:

$$\sqrt{n_1n_3} = n_2, \text{ called geometric mean.}$$

Under this condition the magnitude of the reflection coefficients at the two interfaces is equal and their signs are opposite; destructive interference between the reflected waves occurs and a minimum in reflection under normal incidence is achieved.